# TECHNICAL REPORT

# IEC TR 61000-1-3

First edition 2002-06

PUBLICATION FONDAMENTALE EN CEM BASIC EMC PUBLICATION

# Electromagnetic compatibility (EMC) -

Part 1-3: General – The effects of high-altitude EMP (HEMP) on civil equipment and systems

Compatibilité électromagnétique (CEM) -

Partie 1-3: Généralités – Effets des impulsions électromagnétiques à haute altitude (IEM-HA) sur les matériels et systèmes civils

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# CONTENTS

FOREWORD......4

| INT        | RODUCTION  | 6   |
|------------|--|-----|
| 1          | Scope  | 7   |
| 2          | Reference documents  | 7   |
| 3          | Definitions  | 7   |
| 4          | General considerations   | 9   |
| 5          | Overview of effects experience   | .10 |
|            | 5.1 Atmospheric testing introduction   | .10 |
|            | 5.2 Simulator testing introduction   |     |
| 6          | Atmospheric nuclear testing experience   | .11 |
|            | 6.1 United States atmospheric test experience – Starfish test  | .11 |
|            | 6.2 Soviet Union atmospheric test experience   |     |
| 7          | HEMP simulator testing with radiated transients  |     |
|            | 7.1 Consumer electronics   |     |
|            | 7.2 Communication radios   |     |
|            | 7.3 Commercial power lines   |     |
|            | <ul><li>7.4 Train power-line coupling experiment</li><li>7.5 HEMP-induced currents on a three-phase line</li></ul>   |     |
| 8          | HEMP simulator testing with conducted transients   |     |
| Ũ          | 8.1 High-voltage power-line equipment  |     |
|            | 8.2 Testing of distribution transformers to conducted HEMP transients  |     |
| 9          | Summary  |     |
|            | liography  | .46 |
|            | ure 1 – Starfish-Honolulu burst geometry, with the X indicating the location of<br>Inston Atoll  | .12 |
| Fig        | ure 2 – Front page of New York Tribune, European Edition, 10 July 1962   | .13 |
| Fig        | ure 3 – Ferdinand Street (Honolulu, Hawaii) series lighting system in 1962   | .14 |
| Fig<br>tim | ure 4 – The amplitudes of the computed early-time HEMP E-field components versus e for the near end of the 500-km telecom line   | .15 |
|            | ure 5 – The amplitudes of the computed early-time HEMP E-field components versus e for the far end of the 500-km telecom line  | .16 |
|            | ure 6 – Computed transverse late-time HEMP magnetic flux density at the earth's face at ground ranges of 433 km and 574 km from the surface zero point   | .17 |
| 80-        | ure 7 – Computed early-time HEMP load voltage versus time for the far end of the km long subline 2 (the top figure shows the earliest time, while the bottom figure bows a later time view)                | .18 |
| end        | ure 8 – Computed early-time HEMP short-circuit current versus time for the near<br>d of the 80 km long subline 2 (the top figure shows the earliest time, while the bottom<br>ure shows a later time view) | .19 |
| of t       | ure 9 – Computed early-time HEMP short-circuit current versus time for the far end the 80 km long subline 2 (the top figure shows the earliest time, while the bottom ure shows a later time view)         | .20 |
|            |  |     |

Figure 10 – Time response for a typical antenna cable coupled current measured at WRF .....23

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| Figure 11 – Time response for a typical telephone cable coupled current measured at WR   | F.23 |
|--|------|
| Figure 12 – Time response for a typical power cable coupled current measured at WRF  | 24   |
| Figure 13 – Time response for a typical speaker wire coupled current measured at WRF   | 24   |
| Figure 14 – Time response for a typical computer keyboard coupled current measured at WRF  | 25   |
| Figure 15 – Geometry of the medium voltage (MV) power lines with respect to the EMP simulator  | 29   |
| Figure 16 – Comparison of measured (left) and calculated (right) HEMP simulator-<br>induced voltage (line to ground) at position M in figure 15, where the line turns 90°  | 30   |
| Figure 17 – Comparison of the measured currents in amperes at four different locations: 1 and 2 at 48 m on either side of the simulator centreline (points M and N in figure 15), and 3 and 4 near the far end of the line (near point Q in figure 15) | 31   |
| Figure 18 – Geometry for HEMP simulation test of locomotive with single power line   | 32   |
| Figure 19 – Measured HEMP-induced current on power line directly above left end of locomotive  | 33   |
| Figure 20 – Geometry for three-phase line placed under a hybrid HEMP simulator   | 34   |
| Figure 21 – Comparison of measured (solid line) and calculated (dashed line) currents flowing on the shielding wire  | 35   |
| Figure 22 – HEMP current measured in the centre of one of the open-circuited phase wires when the grounding wire was removed   | 36   |
| Figure 23 – Experimental HEMP investigation of high-voltage equipment showing the importance of testing power lines when they are energized. Note that the lower figure b) is for a 110-kV power line  | 39   |
| Figure 24 – Simulation of HEMP effects on a 110 kV power line under operating voltage  | 40   |
| Figure 25 – Investigation of HEMP effects on high-voltage transformers   | 41   |
| Figure 26 – Simulation of HEMP effects on a mobile diesel power station under operating voltage  | 42   |
| Figure 27 –Types of interference caused by HEMP penetration through the electric power supply system   | 43   |
| Figure 28 – HEMP test layout for power systems under operation   | 44   |
|  |      |

| Table 1 – Data on the arrester firing voltage as a function of the voltage waveform |    |  |
|---|----|--|
| characteristics (from [6])  | 21 |  |
| Table 2 – The peak pulse currents in kA damaging the fuse SN-1 (from [6])           | 21 |  |
| Table 3 – Summary of operational observations at FEMPS [7]                          | 22 |  |
| Table 4 – Summary of information on radios tested [8]                               | 26 |  |
| Table 5 – Summary of distribution transformer tests [15]                            | 38 |  |

#### INTERNATIONAL ELECTROTECHNICAL COMMISSION

#### ELECTROMAGNETIC COMPATIBILITY (EMC) -

## Part 1-3: General – The effects of high-altitude EMP (HEMP) on civil equipment and systems

#### FOREWORD

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Technical reports do not necessarily have to be reviewed until the data they provide are considered to be no longer valid or useful by the maintenance team.

IEC 61000-1-3, which is a technical report, has been prepared by subcommittee 77C: High power transient phenomena, of IEC technical committee 77: Electromagnetic compatibility. It has the status of a basic EMC publication in accordance with IEC Guide 107.

The text of this technical report is based on the following documents:

| Enquiry draft | Report on voting |
|---------------|------------------|
| 77C/109/CDV   | 77C/121/RVC      |

Full information on the voting for the approval of this technical report can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

This document, which is purely informative, is not to be regarded as an International Standard.

The committee has decided that the contents of this publication will remain unchanged until 2007. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

### INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

#### Part 1: General

General considerations (introduction, fundamental principles) Definitions, terminology

#### Part 2: Environment

Description of the environment Classification of the environment Compatibility levels

#### Part 3: Limits

Emission limits Immunity limits (in so far as they do not fall under the responsibility of product committees)

#### Part 4: Testing and measurement techniques

Measurement techniques Testing techniques

#### Part 5: Installation and mitigation guidelines

Installation guidelines

Mitigation methods and devices

#### Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts published either as International Standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: IEC 61000-6-1).

## ELECTROMAGNETIC COMPATIBILITY (EMC) -

## Part 1-3: General – The effects of high-altitude EMP (HEMP) on civil equipment and systems

#### 1 Scope

The purpose of this part of IEC 61000 is to describe the effects that have occurred during actual and simulated electromagnetic pulse testing throughout the world. These effects include those observed during the high-altitude nuclear tests conducted by the United States and the Soviet Union in 1962, and the HEMP simulator tests conducted by many countries during the years after atmospheric testing ended. In addition to direct effects, this technical report also contains information on HEMP coupling to "long lines" as it is important to verify that particular levels of currents and voltages can be induced by HEMP on these lines; this provides a basis for direct injection testing of electronic equipment. It should be noted that, in most cases, the electrical equipment tested or exposed did not contain the sensitive electronics in use today. Also it should be emphasized that all tests and exposures did not produce failure of the equipment; factors such as the geometry of the HEMP interaction and the electromagnetic shielding of the equipment are variables that can produce differing results. The description of these effects is intended to illustrate the seriousness of the possible effects of HEMP on modern electronic systems.

#### 2 **Reference documents**

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161:1990, International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility

IEC 61000-2-9, *Electromagnetic compatibility (EMC) – Part 2: Environment – Section 9: Description of HEMP environment – Radiated disturbance*. Basic EMC publication

IEC 61000-2-10: Electromagnetic compatibility (EMC) – Part 2-10: Environment – Description of HEMP environment – Conducted disturbance

IEC 61000-4-32: *Electromagnetic compatibility (EMC) – Part 4-32: Testing and measurement techniques – HEMP simulator compendium.* Basic EMC publication<sup>1</sup>

<sup>&</sup>lt;sup>1</sup> To be published.